

Notice of References Cited	Application/Control No. 09/608,311	Applicant(s)/Patent Under Reexamination XIANG ET AL.	
	Examiner Paresh Patel	Art Unit 2829	Page 1 of 1

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*	A	US-3,774,717	11-1973	Chodorow, Marvin	73/61.75
*	B	US-4,364,008	12-1982	Jacques, Steven L.	324/636
*	C	US-5,233,306	08-1993	Misra, Devendra K.	324/601
*	D	US-5,585,722	12-1996	Hosoki et al.	324/318
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Use of time domain spectroscopy for measuring dielectric properties with a coaxial probe," by Gabrial et al. 1986
	V	"Microwave Resonant Cavities for Sending Moisture and Mass of Single Seeds and Kernels," by Kraszewki et al. 1992).
	W	"DIELECTRIC PROBE FOR PERMITTIVITY AND PERMIABILITY MEASUREMENTS AT LOW MICROWAVE FREQUENCIES" by Derray et al. 1992
	X	"A Quasi-Static Analysis of Open-Ended Coaxial Lines" by Misra 1987.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.